

# Reliability test report

## 1. Sample information

<b>Name /Model</b>	BV-5SMDJ24CA	<b>Quatity</b>	300PCS	<b>Source</b>	RD	<b>Batch/Lot No.</b>	FIN21100012
<b>Background</b>	晟驰微电子-定期可靠性						

## 2. Application Information

<b>Applicant</b>	XiaoRui Zhang	<b>Department</b>	RD	<b>Date</b>	2022.2.02	<b>Test category</b>	Reliability Test
<b>Test purpose</b>	定期可靠性						

## 3. Test Method

<b>Reference standard</b>	AEC-Q101/JESD-22 / GJB-128A
<b>Test requirment</b>	According to SPEC

## 4. Experimental Equipment

No.	Equipment name	Model	ID	Calibration date
1	TVS Semiconductor tester	PTHY2900H	BPMS-3010028-118	2021.03.28~2022.03.27
2	TC Chamber	DNT-1518LA-ZK	BPMS-3010010-089	2021.04.23~2022.04.22
3	PCT Chamber	DL/75L	PMS-3040062-120	2021.06.09~2022.06.08
4	Lead-free solder furnace	ZB1510D	PMS-229	2021.04.03—2022.04.02
5	Lightning generator10/700µs	HGV-II	PMY-3040012-028	2021.04.29~2022.04.28

## 5. Test Result

No.	Testing items	Testing conditions	Test data	Test results	Remark
	High Remperature Storage Test	Temperature: 150°C 80%VDMAX Time:168h		OK	
6	High Temperature Storage Test	Temperature: 150°C Time:168h		OK	
7	High-low Temperature Cycle test	Temperature: From -55°C to 150°C ,Dwell time : 30min 100cycles		OK	
8	Pressure cooker Test	Temperature: 121°C Humidity:100% 2atm time:96h		OK	
9	UHAST	Temperature: 130°C Humidity:85% 2atm time:96h		OK	
10	Resistance of soldering heat	Temperature: 260±5°C Time : 10s		OK	
11	Surge test	10/1000s :129A±10T		OK	
<b>Unqualified item description</b>					
<b>Conclusion</b>		OK			

Reported by: Chen Gan  
Date: 2022. 2. 20

Checked by: TengFei Bi  
Date: 2022. 2. 20

Approved by : Yong Liu  
Date: 2022. 2. 20